

# JIS

**JAPANESE INDUSTRIAL STANDARD**

**Testing method for resistivity  
of conductive plastics with  
a four-point probe array**

**JIS K 7194**<sup>—1994</sup>

**Translated and Published**

**by**

**Japanese Standards Association**

**In the event of any doubt arising,  
the original Standard in Japanese is to be final authority.**

## JAPANESE INDUSTRIAL STANDARD

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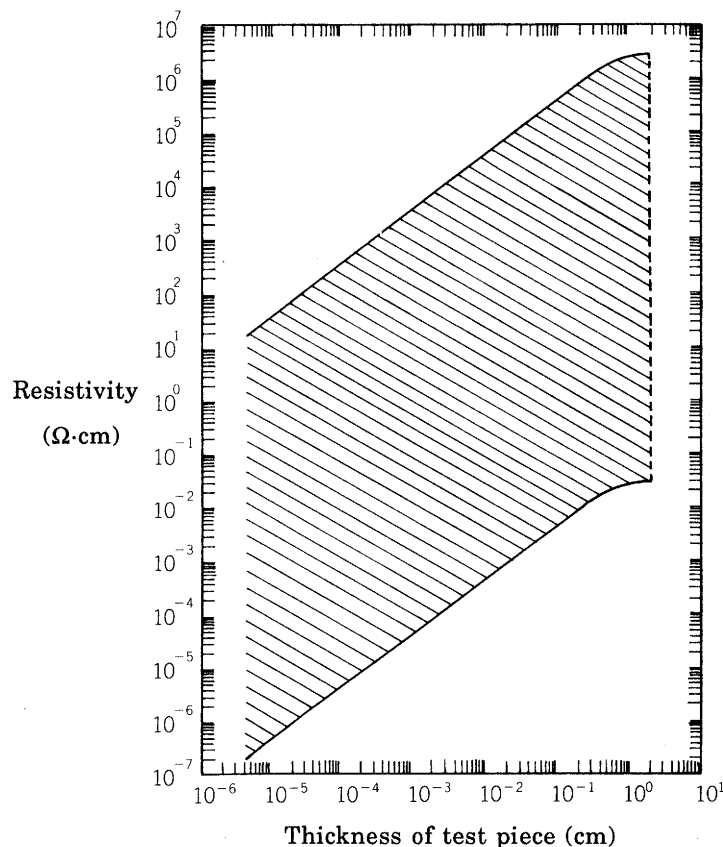
Testing method for resistivity of  
conductive plastics with a four-point probe array

K 7194-1994

1. Scope This Japanese Industrial Standard specifies the testing method for resistivity of conductive plastics with a four-point probe array.

- Remarks 1. In case conductive plastics are coated or laminated on an insulating material, this Standard can be applied if a thickness of only conductive plastics or its nominal value is known. If the thickness of the conductive plastics is not known, this Standard can not be applied.
2. Resistivity which can be measured in this Standard is limited within the range of the slant-lined part given in Fig. 1.

Fig. 1. Measurable range of resistivity



3. The following standards are cited in this Standard:

- JIS B 7502 Micrometer callipers
- JIS B 7507 Vernier, dial and digital callipers
- JIS K 6900 Plastics — Vocabulary [ISO 472: 1988]
- JIS K 7100 Standard atmospheres for conditioning and testing of plastics
- JIS Z 8401 Rules for rounding off of numerical values